DECLARATION OF CONFORMITY

According to FCC Part 15

Applicant Name :	**BIXOLON Co., Ltd.**
Address :	**7th~8th FL, Miraeasset Venture Tower, 685, Sampyeong-dong, Bundang-gu Seongnam-si, Gyeonggi-do, Korea**
Telephone :	**+82-31-218-5582**
Declares that Product :	**Thermal transfer label printer**
Model Name :	**SLP-T40*R**
Report Number :	**CTK-2012-00125**

This device complies with Part 15 of the FCC rules. Operations is subject to the following two conditions: (1) This device may not cause harmful interference, and (2) This device must accept any interference received, including interference that may cause undesired operation.

Test Laboratory:

CTK Co., Ltd.

386-1, Ho-dong, Cheoin-gu, Yongin-si, Gyeonggi-do, 449-100, Korea

Designation Number : 805871

Tel : +82-31-339-9970

Fax : +82-31-339-9855

Responsible Party:

Company Name :	**BIXOLON Co., Ltd.**
Company Address :	**7th~8th FL, Miraeasset Venture Tower, 685, Sampyeong-dong, Bundang-gu Seongnam-si, Gyeonggi-do, Korea**
Phone :	**+82-31-218-5582**
Fax :	**+82-31-218-5589**
Name :	**Hyun-suk Son**
Signature :	

CTK Co., Ltd.
386-1, Ho-dong, Cheoin-gu, Yongin-si, Gyeonggi-do, 449-100, Korea
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www.e-ctk.com

EMC TEST REPORT For FCC

Test Report No.	:	CTK-2012-00125
Date of Issue	:	March 26, 2012
Model/Type No.	:	SLP-T40*R
Kind of Product	:	Thermal transfer label printer
Applicant	:	BIXOLON Co., Ltd.
Applicant Address	:	7th~8th FL, Miraeasset Venture Tower, 685, Sampyeong-dong, Bundang-gu Seongnam-si, Gyeonggi-do, Korea
Manufacturer	:	BIXOLON Co., Ltd.
Manufacturer Address	:	7th~8th FL, Miraeasset Venture Tower, 685, Sampyeong-dong, Bundang-gu Seongnam-si, Gyeonggi-do, Korea
Contact Person	:	Hyun-suk Son / Associate
Telephone	:	+82-31-218-5582
Received Date	:	February 21, 2012
Test Date	:	Start: March 10, 2012 End: March 16, 2012
Test Results	:	☒ **In Compliance** ☐ **Not in Compliance**

The test results presented in this report relate only to the object tested.

Tested by

Lee Eun-Won
EMC Test Engineer
Date: March 26, 2012

Reviewed by

James Hong
EMC Technical Manager
Date: March 26, 2012

REPORT REVISION HISTORY

Date	Revision	Page No
March 26, 2012	Issued (CTK-2012-00125)	All

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TABLE OF CONTENTS

1.0 General Product Description

1.0.1 Tested Equipment

☒ Unless otherwise indicated, all tests were conducted on Model SLP-T403R.
☒ Tests performed on Model SLP-T403R were considered to be representative of Model(s) SLP-T40*R.

1.0.2 Equipment Size, Mobility and Identification

Dimensions: 214(W) by 310(L) by 195(H) ☒ ㎜
Mobility: ☒ Table-top ☐ Floor-standing ☐ Built-in ☐ Portable
Serial No.: Prototype

1.0.3 Electrical Ratings

[Switching Power Adapter]
Input: 100-240 Vac, 50/60 ㎐, 1.5 A
Output: 24 Vdc, 2.5 A

[EUT]
Input: 24 Vdc
Output: -

1.0.4 Test Voltage & Frequency

Unless indicated otherwise on the individual data sheet or test results, the test voltage and frequency was as indicated below.

Voltage: 120 Vac
Frequency: 60 ㎐

1.0.5 Clock & Other Frequencies Utilized

50 ㎒

1.1 Model Differences

- Models (SLP-T40*R) is identical to each other only except for below chart.

*	It can be numerical 0 to 9.
Ex)	0; 200dpi printing resolution (SLP-T400R)
	3; 300dpi printing resolution (SLP-T403R)

- Model SLP-T403R was tested.

1.2 Device Modifications

The following modifications were necessary for compliance.

Not applicable

1.3 EUT Configuration(s)

See Appendix B for individual test set-up configuration(s). The following peripheral devices and/or interface cables were connected during the measurement:

☒ Peripheral Devices

Device	Manufacturer	Model No.	Serial No.
Switching Power Adapter (for EUT)	I.T.E. POWER SUPPLY	FSP060-RAA	-
Personal Computer	SAMSUNG	DM-V400	ZYZF9WAZC01489B
LCD Monitor	DELL INC.	SE198WFPf	CN-0RR716-72872-81T-0WGI
Mouse (USB type)	Dongguan Primax Electronis Ltd	N3+ Optical	K045205911
Keyboard (PS/2 type)	MONTEREY INTERNATIONAL CORP.	K65ZCH301115	ZCH3011

☒ Cable Description

#	Description	Ferrite Core	Length (m)	Other Details
1	AC power Cable, Unshielded	No	1.8	Connect to AC Power
2	AC power Cable, Unshielded	No	1.8	Connect to AC Power
3	Video Cable, Shielded	Yes	1.8	Between a Personal Computer and a LCD Monitor
4	Keyboard(PS/2) Cable, Shielded	No	1.5	Connect to a Personal Computer
5	Mouse(USB) Cable, Shielded	No	1.5	Connect to a Personal Computer
6	Serial Cable, Shielded	No	2.0	Between a Personal Computer and the EUT
7	Parallel Cable, Shielded	Yes	2.0	Between a Personal Computer and the EUT
8	USB Cable, Shielded	No	1.5	Between a Personal Computer and the EUT
9	DC IN Cable, Unshielded	Yes	1.5	Between the EUT and an Switching Power Adapter
10	AC power Cable, Unshielded	No	1.5	Connect to AC Power

1.4 Test Software

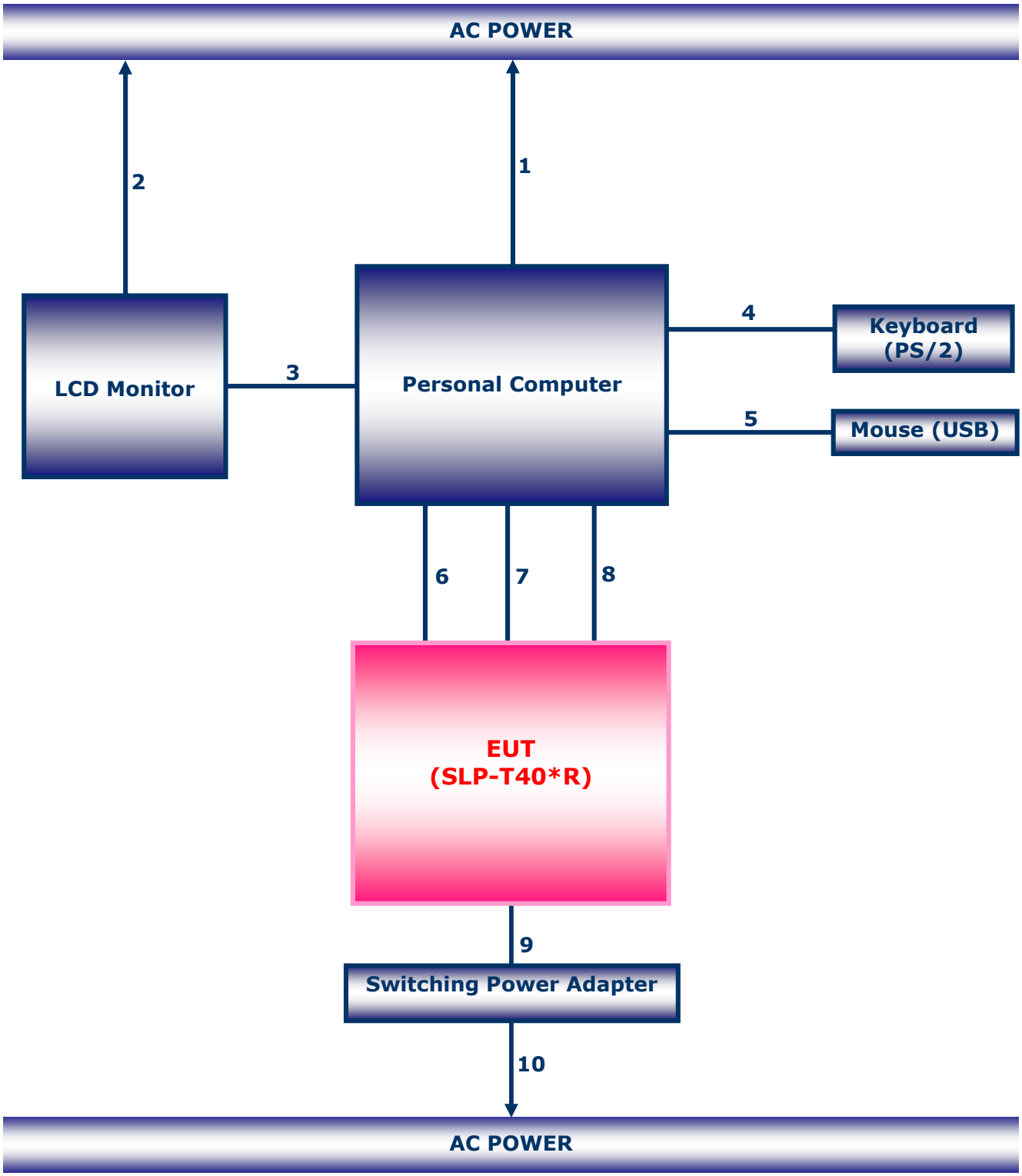
☐ EMC Test V 1.0
☐ Display Test Patterns – V1.5
☐ Ping.exe
☒ Not applicable

1.5 EUT Operating Mode(s)

Equipment under test was operated during the measurement under the following conditions:

☐ Standby
☐ Display circles pattern
☐ Scrolling 'H'
☐ Read / Write
☒ Practice operation – 'H' pattern printing mode
1. USB mode
2. SERIAL mode
3. PARALLEL mode

1.6 Configuration



1.7 Calibration Details of Equipment Used for Measurement

Test equipment and test accessories are calibrated on regular basis. The maximum time between calibrations is one year or what is recommended by the manufacturer, whichever is less. All test equipment calibrations are traceable to the Korea Research Institute of Standards and Science (KRISS), therefore, all test data recorded in this report is traceable to KRISS.

1.8 Test Facility

The measurement facility is located at 386-1, Ho-dong, Cheoin-gu, Yongin-si, Gyeonggi-do, 449-100, Korea. The sites are constructed in conformance with the requirements of ANSI C63.7, ANSI C63.4 and CISPR Publication 22.

1.9 Measurement Procedure

Preliminary AC power line conducted emissions tests were performed shielded room. To find worst mode, several typical mode and typical cable position were tested.
Final AC power line conducted emissions test was performed shielded room. (location is same as Preliminary test)
Based on the preliminary tests of the EUT, final test was proceeded worst case test mode and cable configuration.

Preliminary radiated emissions test were performed anechoic chamber (Distance of antenna and EUT was 3 m). To find worst mode, several typical mode and typical cable position were tested and peak level and frequency were recorded.

Final radiated emissions test was performed Open Area Test Site. Based on the preliminary tests of the EUT, final test was proceeded worst case test mode and cable configuration.

* Measurement procedures was In accordance with ANSI C63.4-2003 7.2.3, 7.2.4, 8.3.1.1, 8.3.1.2

1.10 Laboratory Accreditations and Listings

Country	Agency	Scope of Accreditation	Logo
USA	**FCC**	3 m & 10 m OATS, 3 m & 10 m SAC and Conducted Test Site to perform FCC Part 15/18 measurements	805871
JAPAN	**VCCI**	10 m OATS, 3 m & 10 m SAC and Conducted Test Site	R-948, C-986, T-1843, R-3627, G-387
KOREA	**KCC**	EMI (10 m OATS, 10 m SAC and Conducted Test Site) EMS (ESD, RS, EFT/Burst, Surge, CS, Magnetic, Dips and Interruptions)	No. 51, KR0025

2.0 Emissions Test Regulations

The emissions tests were performed according to following regulations:

☐ EN 61000-6-3:2007		
☐ EN 61000-6-4:2007		
☐ EN 55011:2007 +A2:2007	☐ Group 1 ☐ Class A	☐ Group 2 ☐ Class B
☐ EN 55013:2001 +A1:2003 +A2:2006		
☐ EN 55014-1:2006 ☐ EN 55014-1:2006 +A1:2009		
☐ EN 55015:2006 +A1:2007 +A2:2009		
☐ EN 61204-3:2000	☐ Class A	☐ Class B
☐ EN 61131-2:2007		
☐ EN 61326-1:2006	☐ Class A	☐ Class B
☐ EN 55022:2006	☐ Class A	☐ Class B
☐ EN 61000-3-2:2006 +A1:2009 +A2:2009		
☐ EN 61000-3-3:2008		
☐ VCCI V-3/2010.04	☐ Class A	☐ Class B
☐ AS/NZS CISPR22:2006	☐ Class A	☐ Class B
☒ FCC Part 15 Subpart B	☐ Class A	☒ Class B
☐ CISPR 22:2006	☐ Class A	☐ Class B

2.1 Conducted Voltage Emissions

Test Date
March 10, 2012

Test Location
Shielded Room

Test Equipment

	Name of Equipment	Manufacturer	Model No.	Serial No.	Due Date
☒	EMI Test Receiver	Rohde & Schwarz	ESCI3	100032	2013-02-09
☒	LISN	Rohde & Schwarz	ENV216	101235	2012-08-18
☒	LISN	Rohde & Schwarz	ENV216	101236	2012-08-06
☐	EMI Test Receiver	Rohde & Schwarz	ESHS30	828144/002	2013-02-09
☐	LISN	Rohde & Schwarz	ENV216	101150	2013-02-09
☐	LISN	EMCO	3825/2	9607-2575	2012-07-06

Frequency Range of Measurement
150 ㎑ to 30 ㎒

Instrument Settings
IF Band Width: 9 ㎑

Test Results
The requirements are: ☒ MET ☐ NOT MET ☐ NOT APPLICABLE

Frequency (㎒)	Measured Data (㏈㎶)	Margin (㏈)	Remark
19.405 500	39.6	10.4	Average (SERIAL mode)

Remarks
Test was performed in USB, SERIAL, PARALLEL mode
The emission of SERIAL mode was higher, only the test results of SERIAL mode is listed in Appendix A.
See Appendix A for test data.

2.2 Radiated Electric Field Emissions

Test Date
March 16, 2012

Test Location
Testing was performed at a test distance of:
☐ 10 m OATS ☐ 3 m OATS
☐ 10 m SAC ☒ 3 m SAC

Test Equipment

	Name of Equipment	Manufacturer	Model No.	Serial No.	Due Date
☐	EMI Test Receiver	Rohde & Schwarz	ESVS30	826638/008	2012-07-07
☒	EMI Test Receiver	Rohde & Schwarz	ESCI7	100814	2012-12-13
☒	ULTRA Broadband Antenna	Rohde & Schwarz	HL562	100203	2013-07-05
☒	AMPLIFIER	Sonoma Instrument Co.	310	291721	2012-03-31
☐	EMI Test Receiver	Rohde & Schwarz	ESCI7	100816	2012-12-16
☐	Double Ridged Guide Antenna	ETS-Lindgren	3115	00078894	2013-03-22
☐	PREAMPLIFIER	Agilent Technologies	8449B	3008A02307	2012-11-17

Frequency Range of Measurement
☒ 30 ㎒ to 1 ㎓
☐ 1 ㎓ to 5 ㎓

Instrument Settings
☒ IF Band Width: 120 ㎑
☐ IF Band Width: 1 ㎒

Test Results
The requirements are: ☒ MET ☐ NOT MET ☐ NOT APPLICABLE

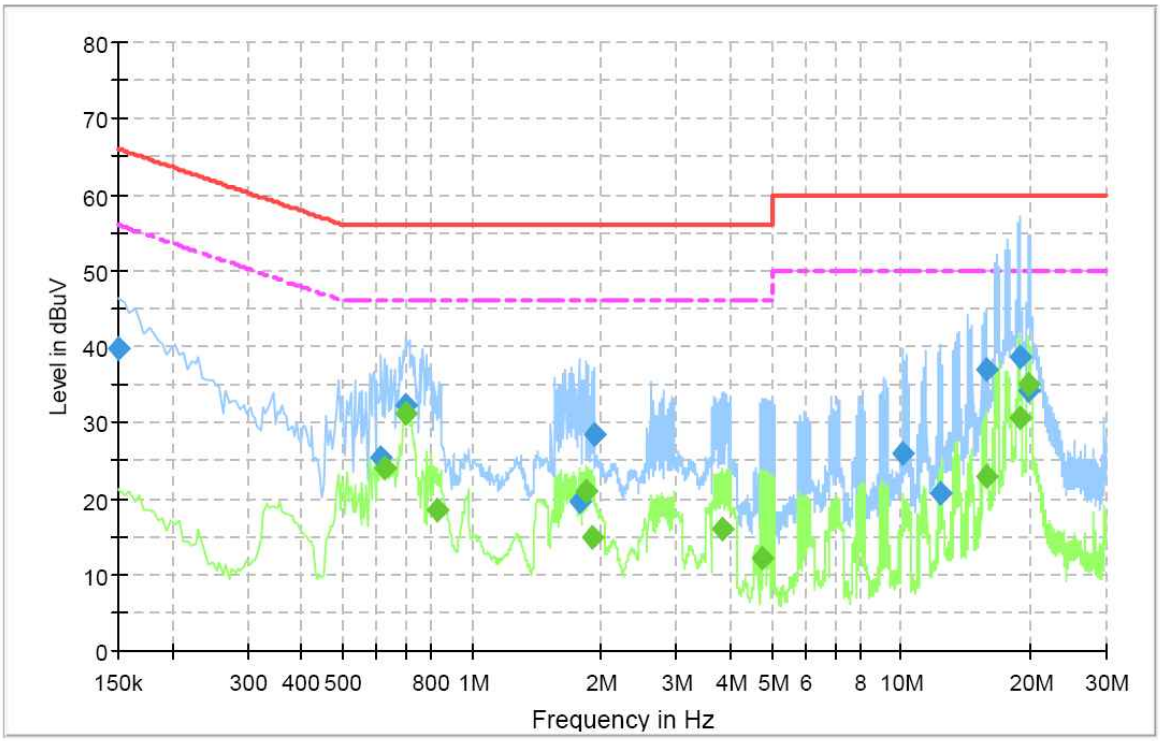
Frequency (㎒)	Measured Data (dBμV/m)	Margin (dB)	Remark
159.352	36.8	6.7	Quasi-peak (PARALLEL mode)

Remarks
Test was performed in USB, SERIAL, PARALLEL mode
The emission of PARALLEL mode was higher, only the test results of PARALLEL mode is listed in Appendix A.
See Appendix A for test data.

APPENDIX A – TEST DATA

Conducted Voltage Emissions

[SERIAL mode - HOT]



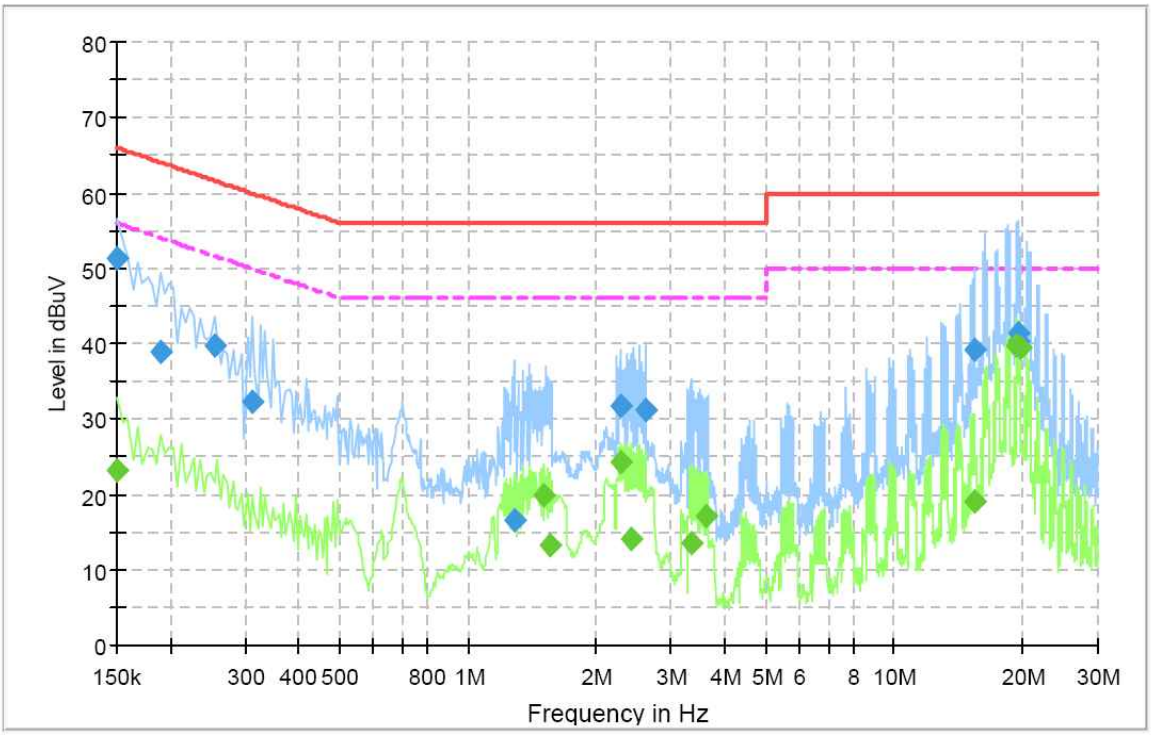
Final Result 1

Frequency (MHz)	QuasiPeak (dBuV)	Meas. Time (ms)	Bandwidth (kHz)	Filter	Line	Corr. (dB)	Margin (dB)	Limit (dBuV)
0.150000	39.6	1000.0	9.000	On	L1	10.2	26.4	66.0
0.613500	25.4	1000.0	9.000	On	L1	10.1	30.6	56.0
0.703500	32.4	1000.0	9.000	On	L1	10.1	23.6	56.0
1.774500	19.5	1000.0	9.000	On	L1	9.9	36.5	56.0
1.918500	28.5	1000.0	9.000	On	L1	9.9	27.5	56.0
10.095000	26.0	1000.0	9.000	On	L1	9.7	34.0	60.0
12.309000	20.6	1000.0	9.000	On	L1	9.8	39.4	60.0
15.724500	36.9	1000.0	9.000	On	L1	9.8	23.1	60.0
18.888000	38.6	1000.0	9.000	On	L1	9.8	21.4	60.0
19.810500	34.1	1000.0	9.000	On	L1	9.8	25.9	60.0

Final Result 2

Frequency (MHz)	Average (dBuV)	Meas. Time (ms)	Bandwidth (kHz)	Filter	Line	Corr. (dB)	Margin (dB)	Limit (dBuV)
0.622500	24.0	1000.0	9.000	On	L1	10.1	22.0	46.0
0.703500	31.3	1000.0	9.000	On	L1	10.1	14.7	46.0
0.825000	18.5	1000.0	9.000	On	L1	10.1	27.5	46.0
1.842000	21.1	1000.0	9.000	On	L1	9.9	24.9	46.0
1.909500	14.8	1000.0	9.000	On	L1	9.9	31.2	46.0
3.822000	16.1	1000.0	9.000	On	L1	9.8	29.9	46.0
4.758000	12.0	1000.0	9.000	On	L1	9.8	34.0	46.0
15.724500	23.0	1000.0	9.000	On	L1	9.8	27.0	50.0
18.924000	30.7	1000.0	9.000	On	L1	9.8	19.3	50.0
19.729500	35.1	1000.0	9.000	On	L1	9.8	14.9	50.0

[SERIAL mode - NEUTRAL]



Final Result 1

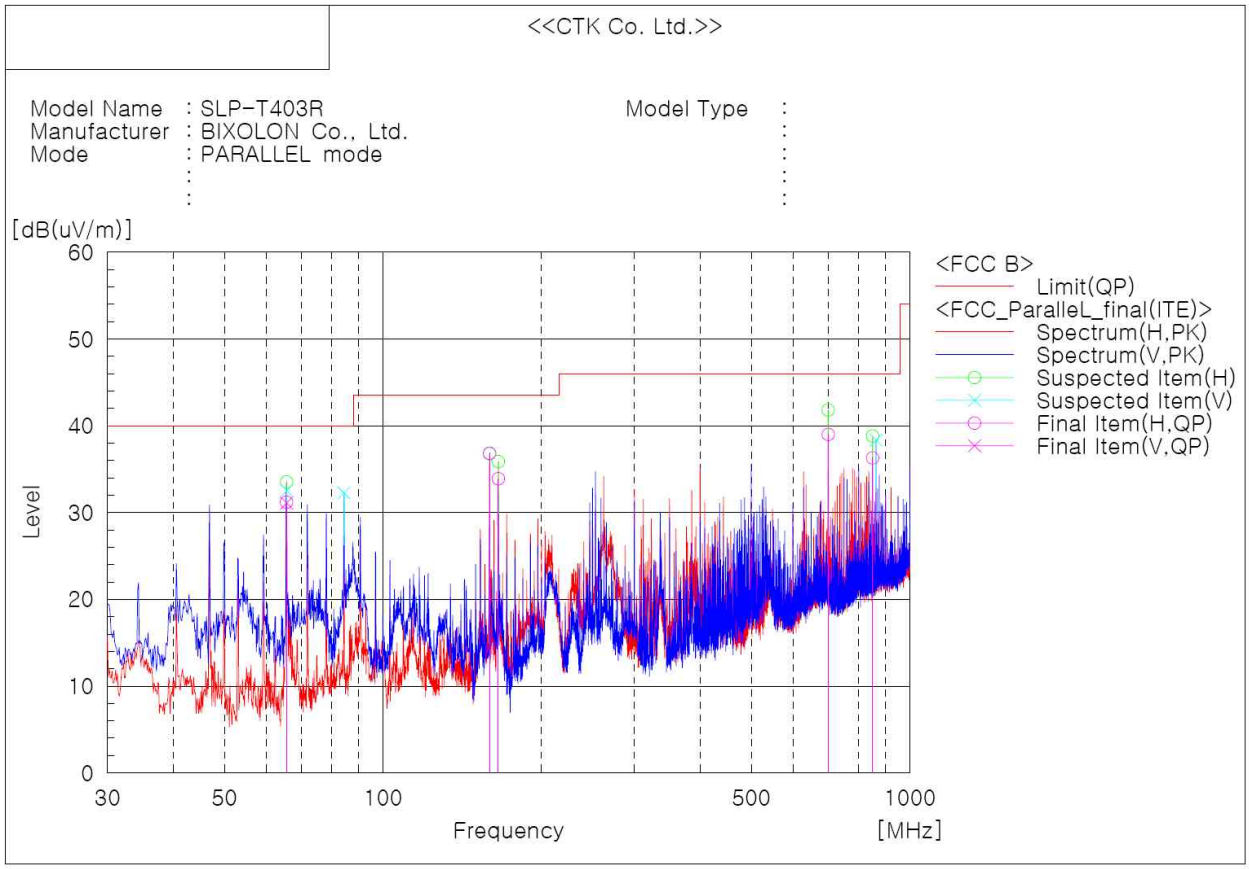
Frequency (MHz)	QuasiPeak (dBuV)	Meas. Time (ms)	Bandwidth (kHz)	Filter	Line	Corr. (dB)	Margin (dB)	Limit (dBuV)
0.150000	51.3	1000.0	9.000	On	N	10.2	14.7	66.0
0.190500	39.0	1000.0	9.000	On	N	10.1	25.0	64.0
0.253500	39.7	1000.0	9.000	On	N	10.1	21.9	61.6
0.312000	32.3	1000.0	9.000	On	N	10.1	27.6	59.9
1.279500	16.7	1000.0	9.000	On	N	10.0	39.3	56.0
2.287500	31.8	1000.0	9.000	On	N	9.9	24.2	56.0
2.611500	31.1	1000.0	9.000	On	N	9.9	24.9	56.0
15.369000	39.1	1000.0	9.000	On	N	9.8	20.9	60.0
19.504500	40.2	1000.0	9.000	On	N	9.9	19.8	60.0
19.644000	41.5	1000.0	9.000	On	N	9.9	18.5	60.0

Final Result 2

Frequency (MHz)	Average (dBuV)	Meas. Time (ms)	Bandwidth (kHz)	Filter	Line	Corr. (dB)	Margin (dB)	Limit (dBuV)
0.150000	23.1	1000.0	9.000	On	N	10.2	32.9	56.0
1.513500	19.8	1000.0	9.000	On	N	9.9	26.2	46.0
1.558500	13.2	1000.0	9.000	On	N	9.9	32.8	46.0
2.278500	24.2	1000.0	9.000	On	N	9.9	21.8	46.0
2.422500	14.2	1000.0	9.000	On	N	9.9	31.8	46.0
3.358500	13.5	1000.0	9.000	On	N	9.8	32.5	46.0
3.624000	17.2	1000.0	9.000	On	N	9.8	28.8	46.0
15.423000	19.2	1000.0	9.000	On	N	9.8	30.8	50.0
19.405500	39.6	1000.0	9.000	On	N	9.9	10.4	50.0
19.720500	39.4	1000.0	9.000	On	N	9.9	10.6	50.0

Radiated Electric Field Emissions

[PARALLEL mode]

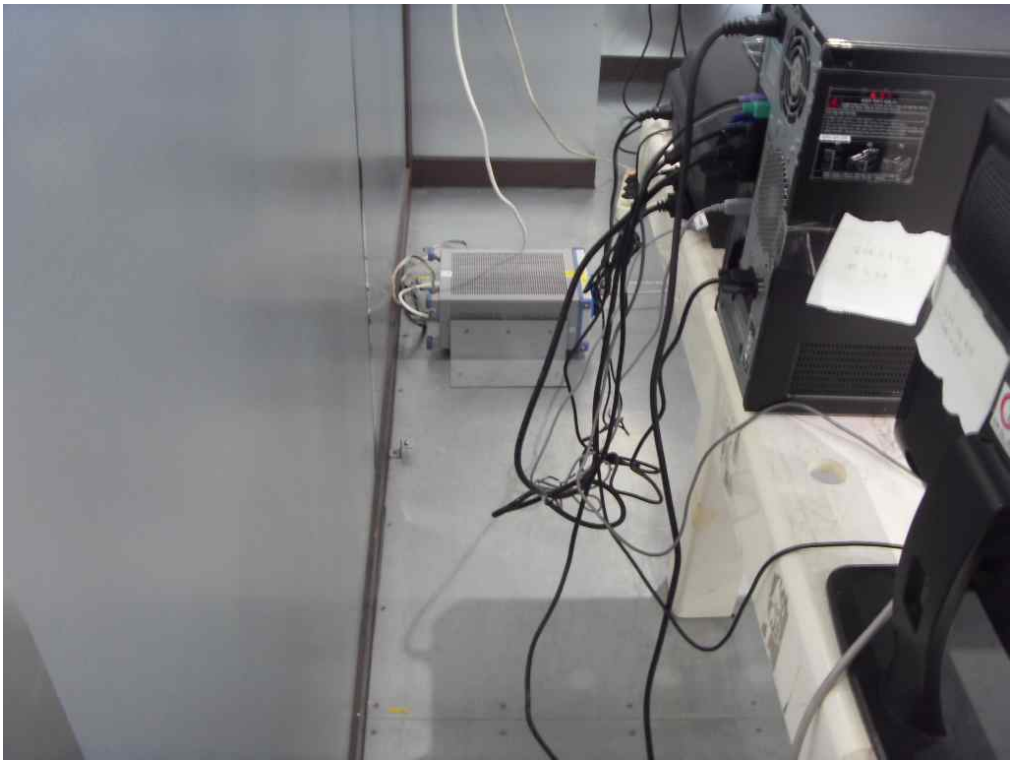


Final Result

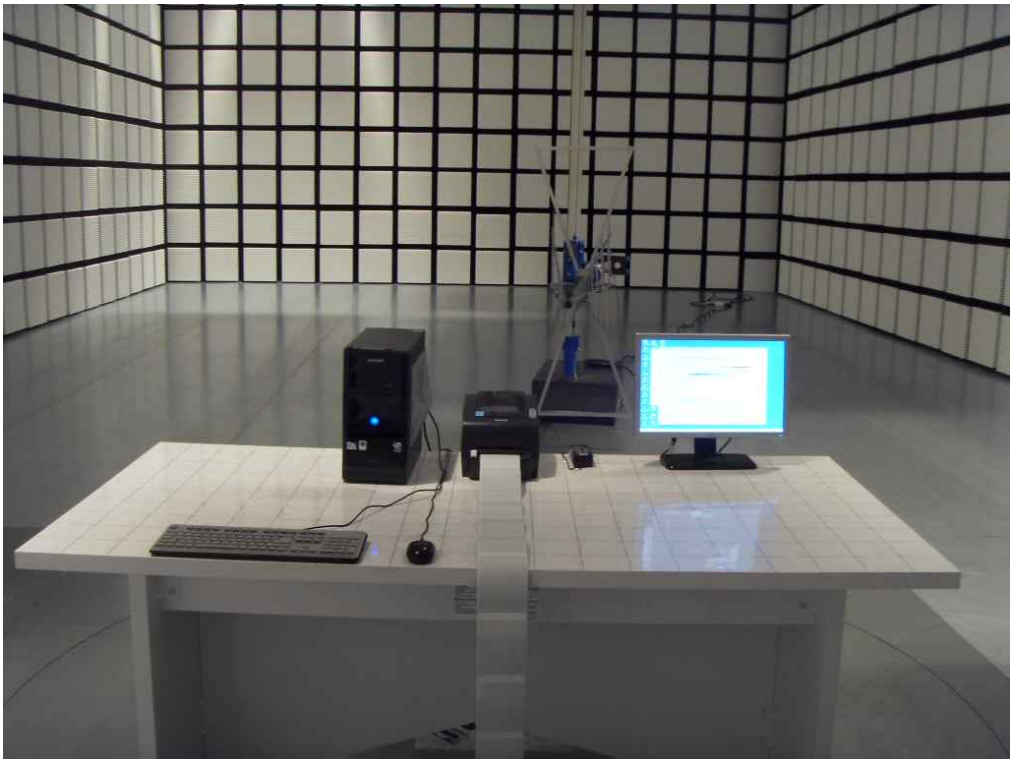
No.	Frequency [MHz]	(P)	Reading QP [dB(uV)]	c.f [dB(1/m)]	Result QP [dB(uV/m)]	Limit QP [dB(uV/m)]	Margin QP [dB]	Height [cm]	Angle [deg]
1	65.620	H	55.3	-24.1	31.2	40.0	8.8	310.0	105.0
2	65.648	V	55.1	-24.0	31.1	40.0	8.9	196.0	256.0
3	159.352	H	57.2	-20.4	36.8	43.5	6.7	223.0	265.0
4	165.558	H	53.8	-19.9	33.9	43.5	9.6	208.0	140.0
5	699.985	H	43.7	-4.7	39.0	46.0	7.0	100.0	200.0
6	850.014	H	38.2	-1.9	36.3	46.0	9.7	212.0	284.0

APPENDIX B - Test Setup Photos and Configuration

Conducted Voltage Emissions



Radiated Electric Field Emissions

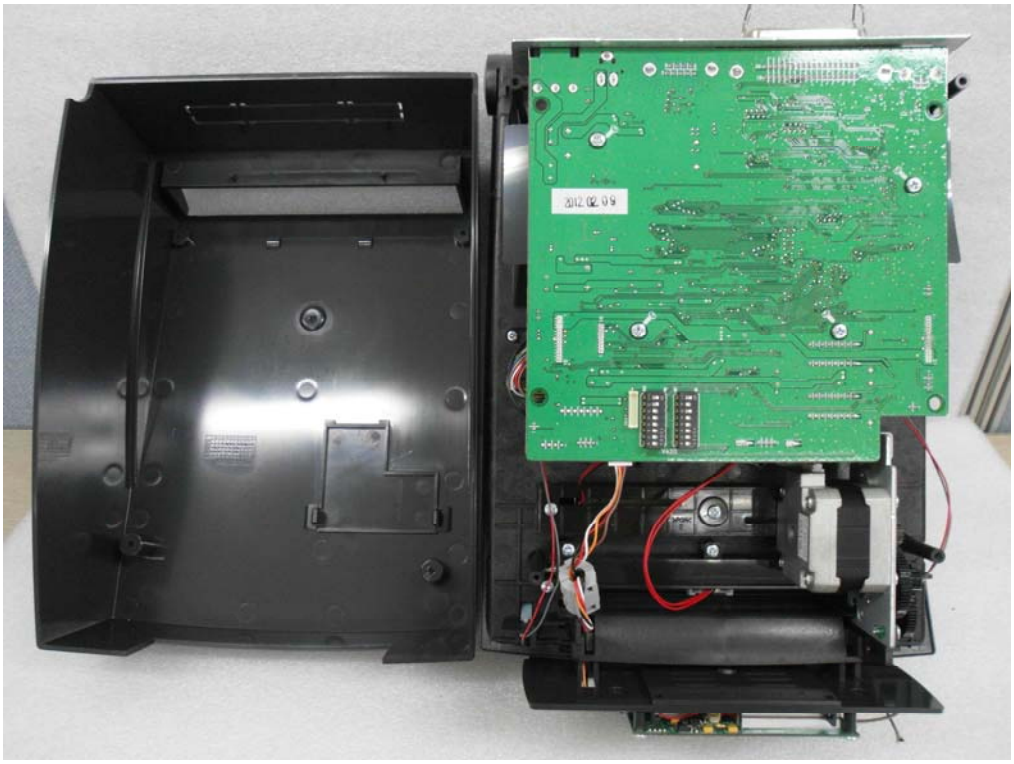


APPENDIX C – EUT Photographs

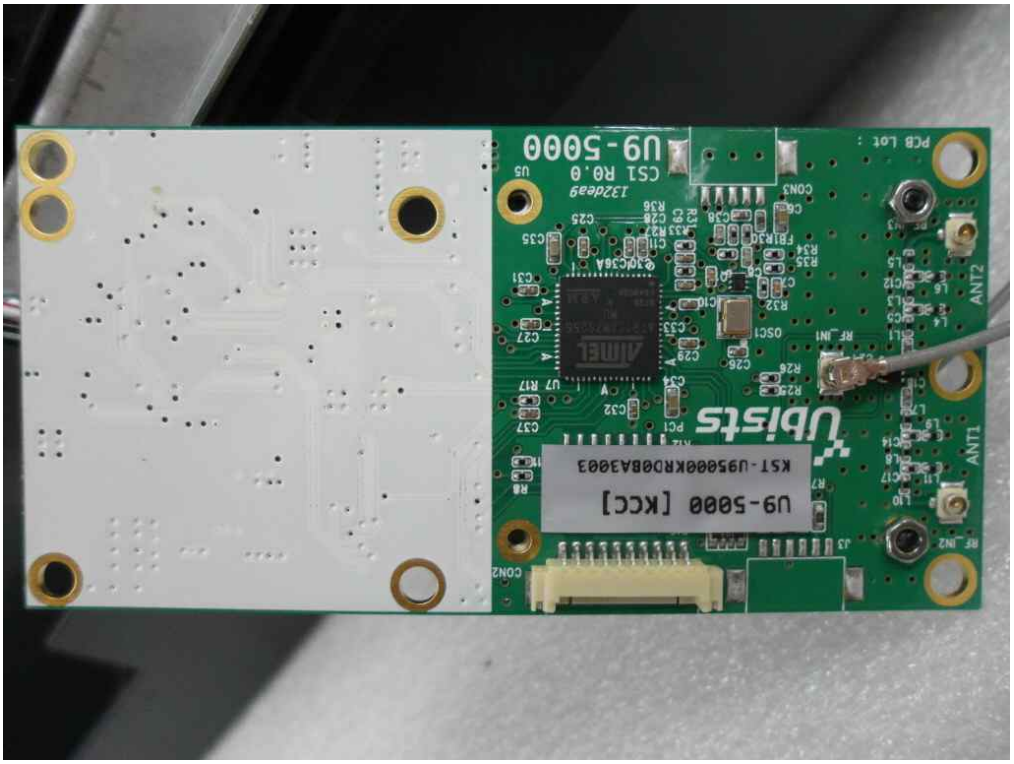
EUT External Photographs

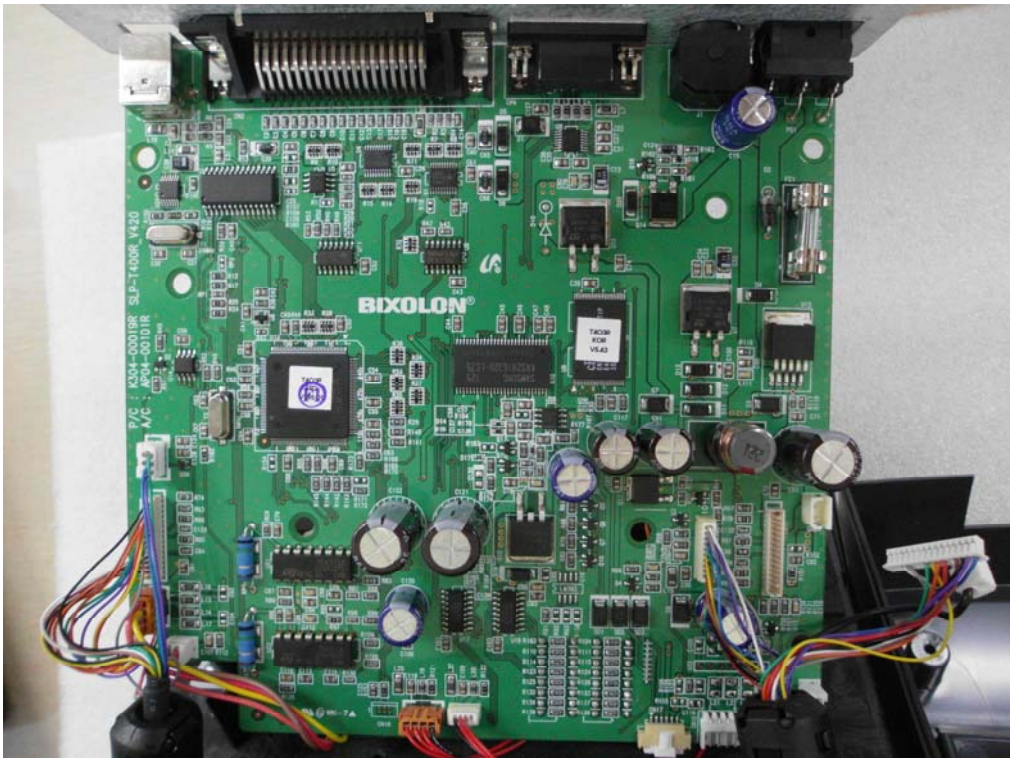
Switching Power Adapter

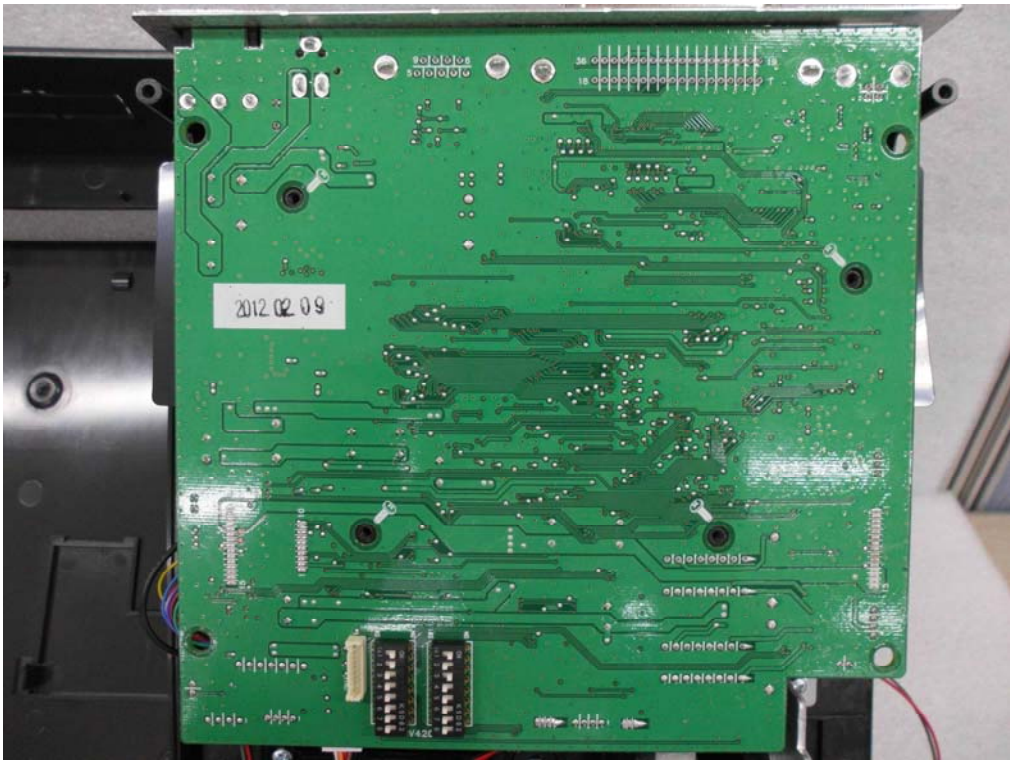
EUT Internal Photographs



PCB







Label and Location